

74F132

Quad 2-Input NAND Schmitt Trigger

General Description

The F132 contains four 2-input NAND gates which accept standard TTL input signals and provide standard TTL output levels. They are capable of transforming slowly changing input signals into sharply defined, jitter-free output signals. In addition, they have a greater noise margin than conventional NAND gates.

Each circuit contains a 2-input Schmitt Trigger followed by level shifting circuitry and a standard FAST™ output struc-

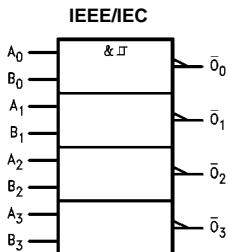
ture. The Schmitt Trigger uses positive feedback to effectively speed-up slow input transitions, and provide different input threshold voltages for positive and negative-going transitions. This hysteresis between the positive-going and negative-going input threshold (typically 800 mV) is determined by resistor ratios and is essentially insensitive to temperature and supply voltage variations.

Ordering Code:

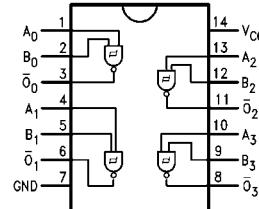
Order Number	Package Number	Package Description
74F132SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
74F132SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F132PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Function Table

Inputs		Outputs
A	B	O
L	L	H
L	H	H
H	L	H
H	H	L

H = HIGH Voltage Level

L = LOW Voltage Level

Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I _H /I _L Output I _{OH} /I _{OL}
A _n , B _n O _n	Inputs Outputs	1.0/1.0 50/33.3	20 μA/-0.6 mA -1 mA/20 mA

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Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V_{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)	
Standard Output	-0.5V to V_{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I_{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

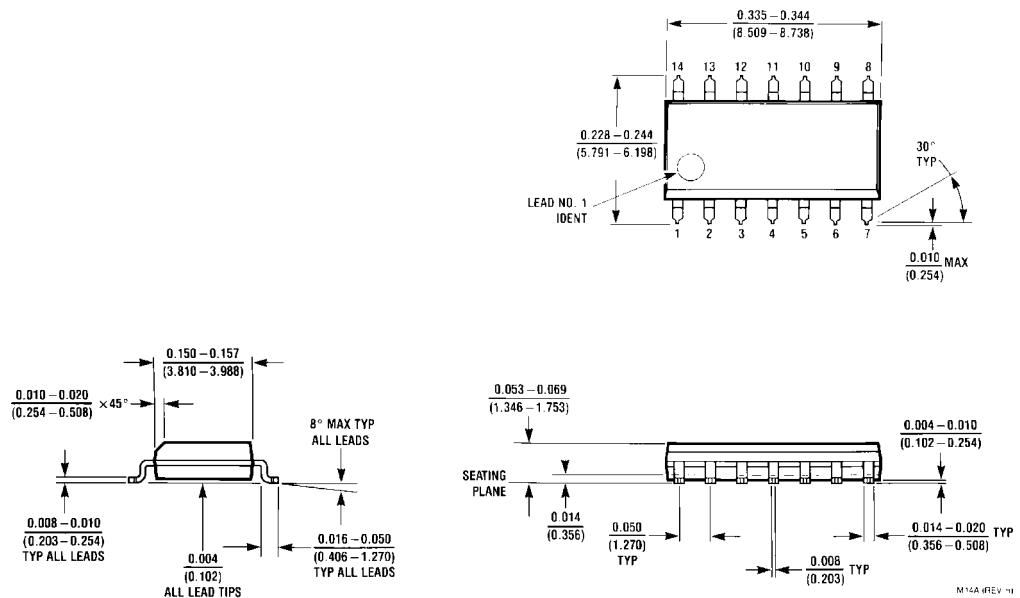
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V_{CC}	Conditions
V_{T+}	Positive-going Threshold	1.5		2.0	V	5.0	
V_{T-}	Negative-going Threshold	0.7		1.1	V	5.0	
ΔV_T	Hysteresis ($V_T^+ - V_T^-$)	0.4			V	5.0	
V_{CD}	Input Clamp Diode Voltage			-1.2	V	Min	$I_{IN} = -18 \text{ mA}$
V_{OH}	Output HIGH Voltage 10% V_{CC}	2.5			V	Min	$I_{OH} = -1 \text{ mA}$
	5% V_{CC}	2.7					$I_{OH} = -1 \text{ mA}$
V_{OL}	Output LOW Voltage	10% V_{CC}		0.5	V	Min	$I_{OL} = 20 \text{ mA}$
I_{IH}	Input HIGH Current			5.0	μA	Max	$V_{IN} = 2.7V$
I_{BVI}	Input HIGH Current Breakdown Test			7.0	μA	Max	$V_{IN} = 7.0V$
I_{CEX}	Output HIGH Leakage Current			50	μA	Max	$V_{OUT} = V_{CC}$
V_{ID}	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$ All Other Pins Grounded
I_{OD}	Output Leakage Circuit Current			3.75	μA	0.0	$V_{OD} = 150 \text{ mV}$ All Other Pins Grounded
I_{IL}	Input LOW Current			-0.6	mA	Max	$V_{IN} = 0.5V$
I_{OS}	Output Short-Circuit Current	-60		-150	mA	Max	$V_{OUT} = 0V$
I_{CCH}	Power Supply Current			17.0	mA	Max	$V_O = \text{HIGH}$
I_{CCL}	Power Supply Current			18.0	mA	Max	$V_O = \text{LOW}$

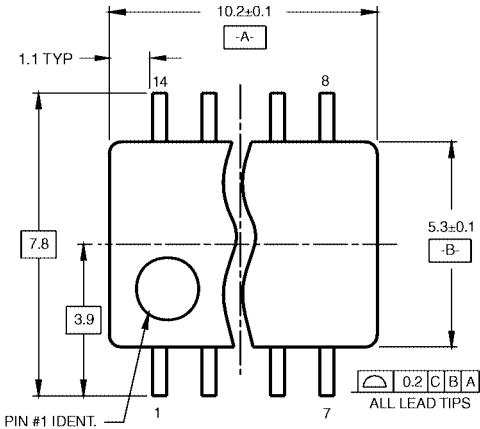
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^\circ\text{C}$			$T_A = 0^\circ\text{C} \text{ to } +70^\circ\text{C}$		Units
		Min	Typ	Max	Min	Max	
t_{PLH}	Propagation Delay A_n, B_n to \bar{O}_n	4.0		10.5	3.5	12.0	ns
		5.0		12.5	5.0	13.0	

Physical Dimensions inches (millimeters) unless otherwise noted

14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
Package Number M14A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



14 13

9 8

5.01 TYP

9.27 TYP

1 2

6 7

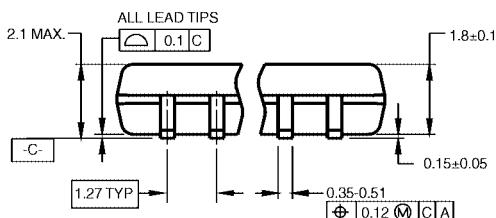
(2.13 TYP)

1.27 TYP

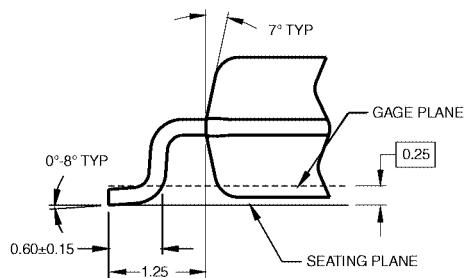
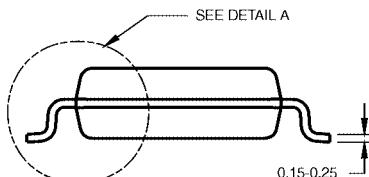
1.23 TYP

0.6 TYP

LAND PATTERN RECOMMENDATION



DIMENSIONS ARE IN MILLIMETERS



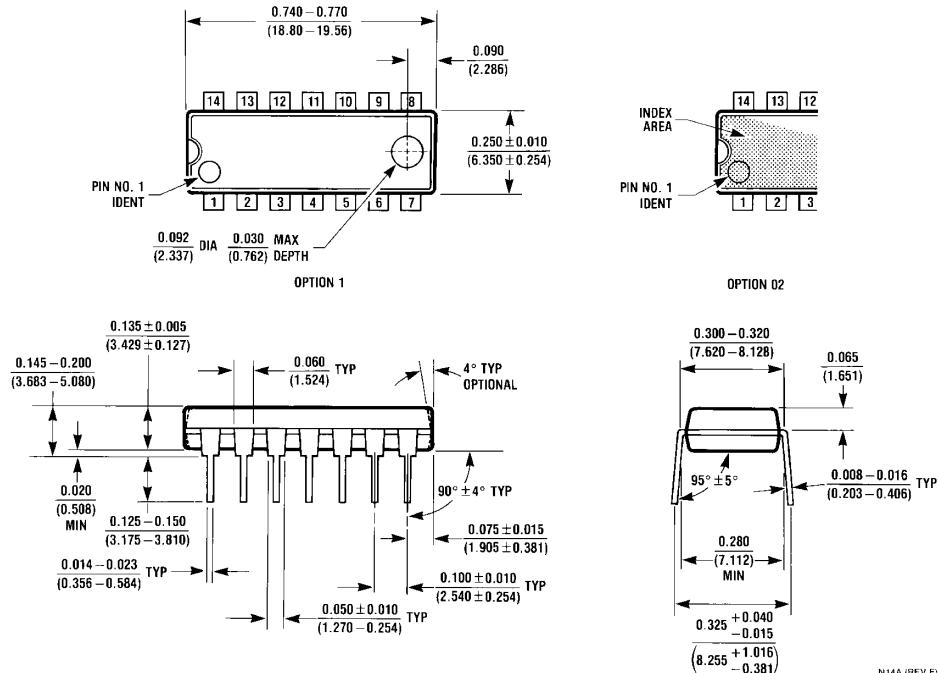
NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION,
ESTABLISHED IN DECEMBER, 1998.
 - B. DIMENSIONS ARE IN MILLIMETERS.
 - C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD
FLASH, AND TIE BAR EXTRUSIONS.

M14DRevB1

**14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M41D**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N14A**

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